

Notice of References Cited	Application/Control No. 10/634,038	Applicant(s)/Patent Under Reexamination CASTLE ET AL.	
	Examiner Alexander J Kosowski	Art Unit 2125	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0193899 A1	12-2002	Shanmugasundram et al.	700/108
	B	US-6,587,744 B1	07-2003	Stoddard et al.	700/121
	C	US-6,584,369 B2	06-2003	Patel et al.	700/100
	D	US-6,594,536 B1	07-2003	Lin et al.	700/99
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Cycle time advantages of mini batch manufacturing integrated metrology in a 300 mm vertical furnace". Noben et al. Semiconductor Manufacturing Symposium, 2001 International. San Jose Ca. 10/08/01-10/10/01, Pages 411-414.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.